

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 09/901,402 | Applicant(s)/Patent Under Reexamination HSIEH ET AL. | |
| | Examiner Ricardo Pizarro | Art Unit 2661 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| | A | US-5,964,831 | 10-1999 | Kearns et al. | 709/201 |
| | B | US-5,950,173 | 09-1999 | Perkowski, Thomas J. | 705/26 |
| | C | US-5,835,696 | 11-1998 | Hess, Gary C. | 714/10 |
| | D | US-5,008,814 | 04-1991 | Mathur, Ashish | 709/221 |
| | E | US-6,772,216 | 08-2004 | Ankireddipally et al. | 709/230 |
| | F | US-6,192,034 | 02-2001 | Hsieh et al. | 370/241 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.